# **BUK7510-55AL**

# N-channel TrenchMOS standard level FET

Rev. 03 — 4 August 2009

**Product data sheet** 

## 1. Product profile

### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- Q101 compliant
- Suitable for thermally demanding environments due to 175 °C rating
- Suitable for use in control systems due to stable operation in linear mode

### 1.3 Applications

- 12 V and 24 V loads
- Automotive systems

- DC motor control
- Repetitive clamped inductive switching

### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	-	55	V
$I_D$	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	[1]	-	-	75	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	300	W
Avalanch	ne ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup} \le$ 55 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	1.1	J
Dynamic	characteristics						
$Q_{GD}$	gate-drain charge	$V_{GS} = 10 \text{ V; } I_D = 25 \text{ A;}$ $V_{DS} = 44 \text{ V; } T_j = 25 \text{ °C;}$ see Figure 15		-	50	-	nC
Static ch	aracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \underline{\text{Figure 12}};$ $\text{see } \underline{\text{Figure 13}}$		-	8.5	10	mΩ

<sup>[1]</sup> Continuous current is limited by package.



2 of 13

N-channel TrenchMOS standard level FET

# **Pinning information**

Table 2. **Pinning information** 

Pin	Symbol	Description	Simplified outline	Graphic symbol	
1	G	gate		_	
2	D	drain	mb	D	
3	S	source			
	D	mounting base; connected to drain	1 2 3	mbb076 S	
			SOT78 (TO-220AB; SC-46)		

#### **Ordering information** 3.

Table 3. **Ordering information** 

**Product data sheet** 

Type number	Package					
	Name	Description	Version			
BUK7510-55AL	TO-220AB; SC-46	Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78			

3 of 13

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	55	V
$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	55	V
$V_{GS}$	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[1][2]	-	122	Α
		$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[3]	-	75	Α
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 10 V; see <u>Figure 1</u>	[3]	-	75	Α
I <sub>DM</sub>	peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed}; \text{ see } \frac{\text{Figure 3}}{}$		-	490	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	300	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	ain diode					
Is	source current	$T_{mb} = 25  ^{\circ}C;$	[1][2]	-	122	Α
		$T_{mb} = 25  ^{\circ}C;$	[3]	-	75	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	490	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 75 A; $V_{sup} \le$ 55 V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	1.1	J
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	see Figure 4	[4][5] [6]	-	-	J

<sup>[1]</sup> Current is limited by power dissipation chip rating.

<sup>[2]</sup> Refer to document 9397 750 12572 for further information.

<sup>[3]</sup> Continuous current is limited by package.

<sup>[4]</sup> Single-shot avalanche rating limited by maximum junction temperature of 175 °C.

<sup>[5]</sup> Repetitive avalanche rating limited by average junction temperature of 170 °C.

<sup>[6]</sup> Refer to AN10273 for further information.

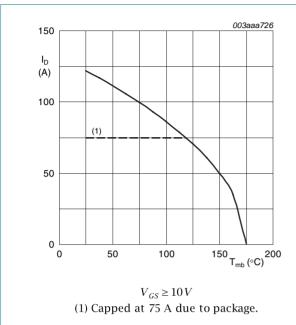


Fig 1. Continuous drain current as a function of mounting base temperature

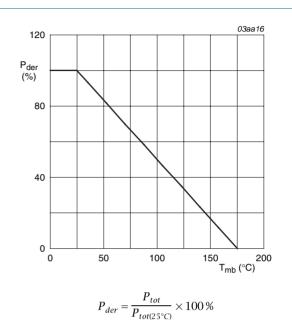
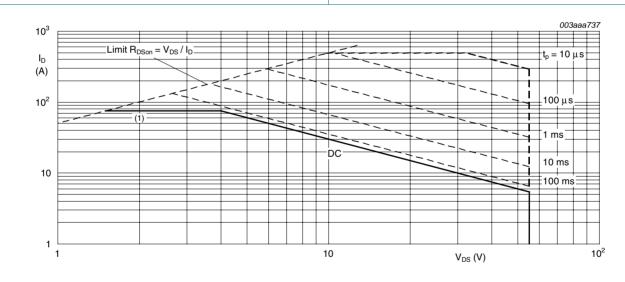
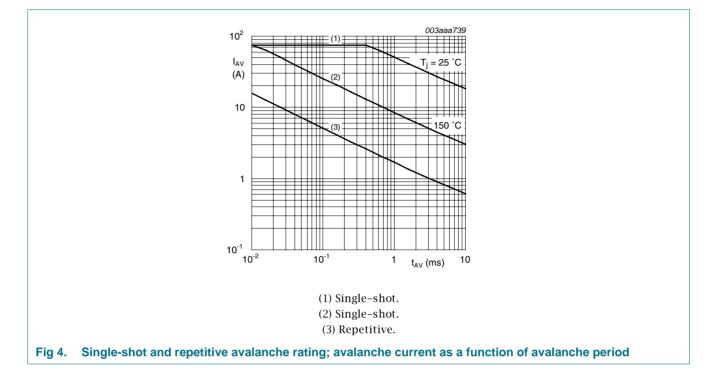


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$  is single pulse (1) Capped at 75 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage



### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 5	-	0.25	0.5	K/W

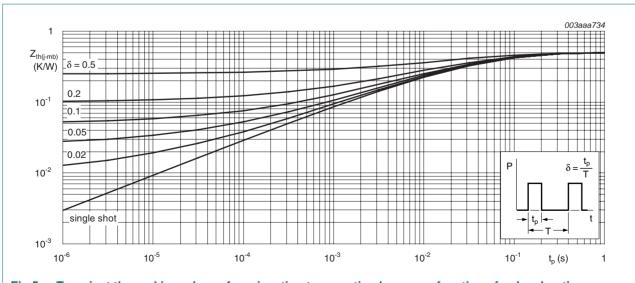


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 6. Characteristics

Table 6. Characteristics

Symbol	Characteristics	Conditions	Min	Turn	Morr	l lm!4
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	aracteristics	L 250 224 T 55.22	<b>50</b>			١,,
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu\text{A};  V_{GS} = 0  \text{V};  T_j = -55 ^{\circ}\text{C}$	50	-	-	V
.,		$I_D = 250 \mu\text{A};  V_{GS} = 0  \text{V};  T_j = 25 ^{\circ}\text{C}$	55	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	2	3	4	V
		$I_D = 1 \text{ mA}$ ; $V_{DS} = V_{GS}$ ; $T_j = -55 \text{ °C}$ ; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	4.4	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see Figure 10; see Figure 11	1	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	500	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = +20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 12; see Figure 13	-	-	20	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 12; see Figure 13	-	8.5	10	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge $I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$		-	124	-	nC
$Q_{GS}$	gate-source charge	T <sub>j</sub> = 25 °C; see <u>Figure 15</u>	-	22	-	nC
$Q_{GD}$	gate-drain charge		-	50	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 15	-	5	-	V
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4710	6280	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	980	1180	pF
C <sub>rss</sub>	reverse transfer capacitance		-	560	770	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	33	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega$ ; $T_j = 25 °C$	-	117	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	132	-	ns
t <sub>f</sub>	fall time		-	95	-	ns
L <sub>D</sub>	internal drain inductance	from contact screw on package to centre of die; T <sub>i</sub> = 25 °C	-	3.5	-	nΗ
		from drain lead 6mm from package to centre of die; T <sub>i</sub> = 25 °C	-	4.5	-	Н
L <sub>S</sub>	internal source inductance	from source lead to source bond pad; T <sub>i</sub> = 25 °C	-	7.5	-	nΗ
Source-d	rain diode	•				
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 14	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	73	-	ns
41		$V_{DS} = 30 \text{ V}; T_i = 25 \text{ °C}$				

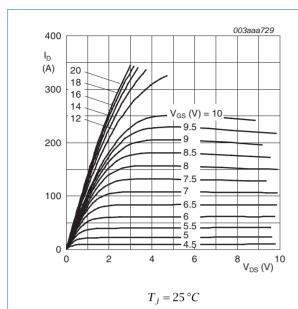
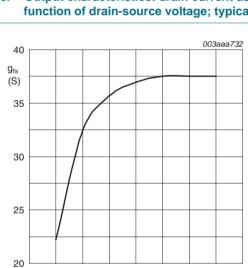


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_i = 25 \,^{\circ}C; V_{DS} = 25 \,^{\circ}V$ 

60 I<sub>D</sub> (A) 80

Forward transconductance as a function of Fig 8. drain current; typical values

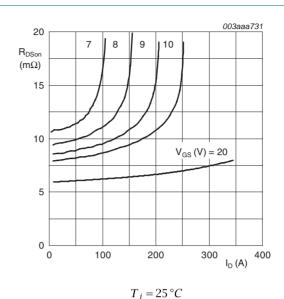


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

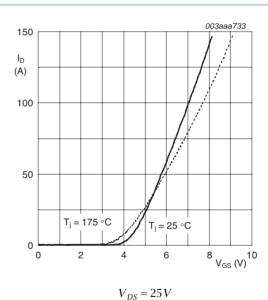
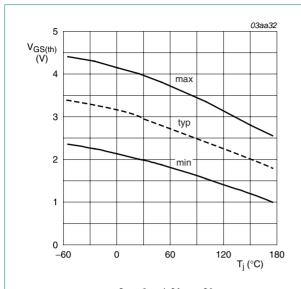
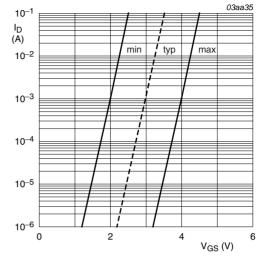


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values



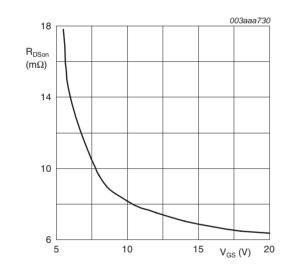
 $I_D = 1 \, mA; V_{DS} = V_{GS}$ 

Fig 10. Gate-source threshold voltage as a function of junction temperature



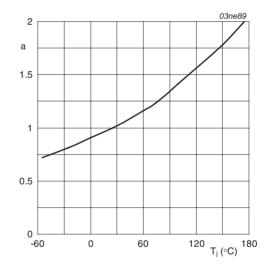
 $T_j = 25$  °C; $V_{DS} = 5V$ 

Fig 11. Sub-threshold drain current as a function of gate-source voltage



 $T_{j} = 25 \,^{\circ}C; I_{D} = 25A$ 

Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

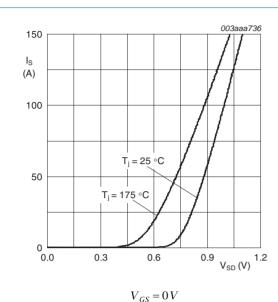
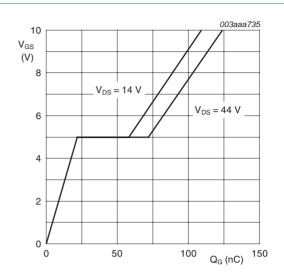
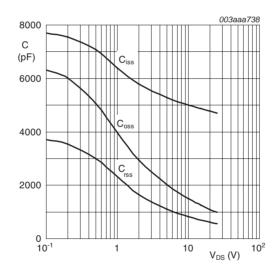


Fig 14. Source current as a function of source-drain voltage; typical values



$$T_i = 25 \,^{\circ}C; I_D = 25A$$

Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

## 7. Package outline

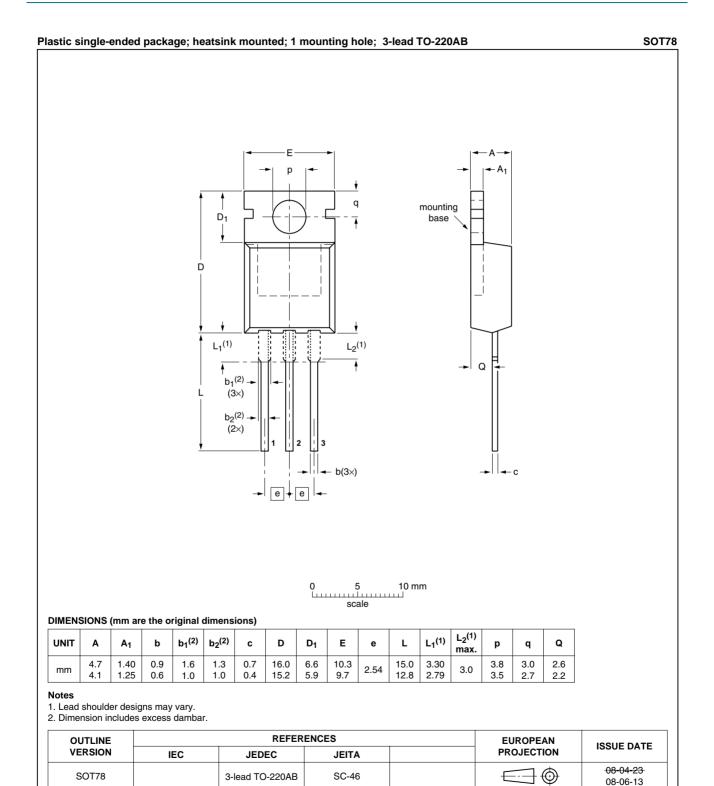


Fig 17. Package outline SOT78 (TO-220AB)

BUK7510-55AL

### N-channel TrenchMOS standard level FET

# 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7510-55AL_3	20090804	Product data sheet	-	BUK7510-55AL_2
Modifications:	<ul> <li>Package or</li> </ul>	utline updated.		
BUK7510-55AL_2	20080103	Product data sheet	-	BUK75_7610_55AL_1
BUK75_7610_55AL_1	20050331	Product data sheet	-	-

### 9. Legal information

### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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# **BUK7510-55AL**

### N-channel TrenchMOS standard level FET

### 11. Contents

1	Product profile	.1
1.1	General description	.1
1.2	Features and benefits	.1
1.3	Applications	.1
1.4	Quick reference data	.1
2	Pinning information	.2
3	Ordering information	.2
4	Limiting values	.3
5	Thermal characteristics	.5
6	Characteristics	.6
7	Package outline	10
В	Revision history	11
9	Legal information	12
9.1	Data sheet status	12
9.2	Definitions	12
9.3	Disclaimers	12
9.4	Trademarks	12
10	Contact information	12

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